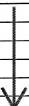


Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 286662US2PCT		SERIAL NO. 10/575,470	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Mitsuhiro YAMASHITA, et al.			
				FILING DATE April 12, 2006		GROUP 2832	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
	AA						
	AB						
	AF						
	AD						
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	AG						
	AH						
	AI						
	AJ						
	AK						
	AF						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
	/TN/	AO 10-294223	11-04-98	JAPAN (w/English Abstract)		X	
		AP 6-334091	12-02-94	JAPAN (w/English Abstract)		X	
		AO 45-33405	12-19-1970	JAPAN		X	
		AP 02-224307	09-06-1990	JAPAN (w/English Abstract)		X	
		AB 2001-155950	06-08-2001	JAPAN (w/English Abstract)		X	
		AT 59-166415	11-08-1984	JAPAN		X	
		AU 03-023604	01-31-1991	JAPAN (w/English Abstract)		X	
	/TN/	AV 07-254515	10-03-1995	JAPAN (w/English Abstract)		X	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						
					<input type="checkbox"/> Additional References sheet(s) attached		
Examiner <u>/Tuyen Nguyen/</u>					Date Considered <u>9/15/2007</u>		

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 286662US2PCT		SERIAL NO. 10/575,470	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Mitsuhiro YAMASHITA, et al.			
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U.S. PATENT DOCUMENTS							
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		AM					
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
/TN/ /TN/	AD	01-206610	08-18-1989	JAPAN (w/English Abstract)		X	
	AP	10-116719	05-06-1998	JAPAN (w/English Abstract)		X	
	AD	09-0007852	01-10-1997	JAPAN (w/English Abstract)		X	
	AK	09-306773	11-28-1997	JAPAN (w/English Abstract)		X	
	AS	272461	12-12-1997	JAPAN (w/English Abstract)		X	
	AT	272642	12-12-1997	JAPAN (w/English Abstract)		X	
	AU	09-330826	12-22-1997	JAPAN (w/English Abstract)		X	
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
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					<input type="checkbox"/> Additional References sheet(s) attached		
Examiner /Tuyen Nguyen/					Date Considered 9/15/2007		

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